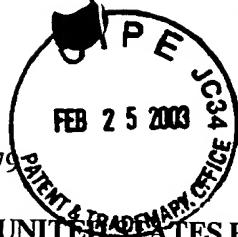


Docket No.: 57454-279



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Hiromitsu SUGIMOTO, et al.

Serial No.: 09/987,893

Filed: November 16, 2001

For: SUBSTRATE TESTING APPARATUS AND SUBSTRATE TESTING METHOD

Group Art Unit: 2829

Examiner: Nguyen, Tung X

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AMENDMENT

Commissioner for Patents  
Washington, DC 20231

Sir:

Please enter the following amendments and remarks in response to the Office action dated November 25, 2002.

IN THE CLAIMS

Please cancel claim 1.

Please amend claims 2 and 7 as follows:

2. (Amended) A substrate testing apparatus comprising:
- a first rail group made of a plurality of rails disposed in parallel with each other;
  - a second rail group made of a plurality of rails disposed in parallel with each other in a direction that crosses said first rail group;
  - a plurality of probe units disposed to cover respective intersections of the rails included in said first rail group and the rails included in said second rail group, all of said probe units being concurrently movable along the rails included in said first rail group and said second rail group;
  - and